Search Notes

Application/Control No.	rol No. Applicant(s)/Patent Reexamination	
10/073,106	YAMAMOTO ET	AL.
Examiner	Art Unit	

Paul D. Kim

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	SEAR	CHED	
Class	Subclass	Date	Examiner
29	831 832 840 841 844 846 851 854	6/30/2005	PK
156	64 356		
	357 358	<b>V</b>	
228	175 227	6/30/2005	PK
	180.22	V	
174	259 260	7/1/2005	PK
361	770 804	2/1/2006	PK
257	686 778		
228	180.22	1	
438	103 106	2/2/2006	PK
	112 118		
	119 127	<b>V</b>	
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1		

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR	
Text Search EAST/NPL (IEEE)	7/1/2005	PK	
Consulted by John Vigushin (361)	2/1/2006	PK	
Scott Geyer (438)	2/2/2006	PK	
Updated Text Search EAST	2/2/2006	PK	